OCT 0 9 2001 B

5/105 E. Willio 11-9-01

**PATENT** 

Docket No.: 50090-332

## IN THE UNITED SEATES PATENT AND TRADEMARK OFFICE

In re Application of

Hisaya MORI, et al.

Serial No.: 09/927,368

Group Art Unit: 2812

Filed: August 13, 2001

Examiner:

For:

APPARATUS AND METHOD FOR TESTING SEMICONDUCTOR INTEGRATED

**CIRCUIT** 

## INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents Washington, DC 20231

Dear Sir:

In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the documents listed on the attached form PTO-1449. It is respectfully requested that the documents be expressly considered during the prosecution of this application, and that the documents be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

This Information Disclosure Statement is being filed within three months of the U.S. filing date OR before the mailing date of a first Office Action on the merits. No certification or fee is required.

The relevance of each non-English language reference, if any, is discussed in the present specification.

Respectfully submitted,

MCDERMOTT, WILL & EMERY

Bene 3 Rutium

Gene Z. Rubinson

Registration No. 33,351

600 13<sup>th</sup> Street, N.W. Washington, DC 20005-3096 (202) 756-8000 GZR:kjw

**Date: October 8, 2001** Facsimile: (202) 756-8087